

High-Voltage, High-Power Silicon N-P-N Power Transistor

For Switching and Linear Applications in Military, Industrial and Commercial Equipment

RCA413

Features:

- Maximum safe-area-of-operation curves
- Low saturation voltage: $V_{CE}^{(sat)} = 0.8V$ max
- High voltage rating: $V_{CEO}^{(sus)} = 325V$
- High dissipation rating: $P_T = 125W$
- Steel Hermetic TO-204MA Package

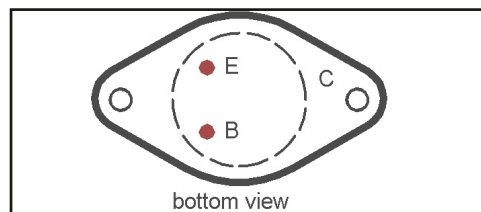
Applications:

- Inverter
- Deflection Circuits
- Switching Regulators
- High-Voltage Bridge Amplifiers
- Ignition circuits

The RCA413 is an epitaxial silicon n-p-n transistor utilizing a multiple-emitter-site structure. The transistor features high breakdown-voltage values make them especially suitable for use in inverters, deflection circuits, switching regulators, high-voltage bridge amplifiers, ignition circuits and other high voltage switching applications.

The RCA413 is supplied in the steel JEDEC TO-204MA hermetic package.

Terminal Designations



bottom view

JEDEC TO-204MA

MAXIMUM RATINGS, Absolute-Maximum Values:

V_{CBO}	400	V
$V_{CEO}^{(sus)}$	325	V
V_{EBO}	5	V
I_C	7	A
I_{CM}	10	A
I_B	2	A
P_T $T_C \leq 25^\circ C$	125	W
P_T $T_C > 25^\circ C$ Derate linearly	0.714	W/°C
T_{stg} T_J	-65 to +200	°C
T_L At distance $\geq 1/32$ in. (0.8mm) from seating plane for 10s max.	230	°C

Characteristic Symbol	Test Conditions				Limits			Units
	Voltage (V)		DC Current (A)		Min.	Typ.	Max.	
	V_{CE}	V_{BE}	I_C	I_B				
I_{CEO}	300				-	-	0.25	mA
I_{CEV}	400	-1.5			-	-	0.25	
I_{CEV} (TC=125°C)	400	-1.5			-	-	0.5	
I_{EBO}		-5			-	-	5	
h_{FE}	5		0.5 ^a		20	-	80	
	5		1 ^a		15	-	-	
$V_{CEO}^{(sus)b}$ (Fig. 3)			0.1		325 ^b	-	-	V
$V_{BE}^{(sat)}$			0.5 ^a	0.05	-	0.8	1.5	
$V_{CE}^{(sat)}$			0.5 ^a	0.05	-	0.15	0.8	
$I_{S/b}^c$ Pulse duration (non-repetitive) = 1s	150				0.1	-	-	A
f_T	10		0.2		-	4	-	MHz
t_r			1	0.1 (IB1)	-	0.35	-	μs
t_s			1	0.1 (IB1)	-	1.4	-	
				-0.5 (-IB2)				
t_f			1	0.1 (IB1)	-	0.15	-	
				-0.5 (-IB2)				
$R_{\theta JC}$	10		5				1.4	°C/W

a Pulsed: pulse duration $\leq 350\mu s$, duty factor = 2%

b CAUTION: The sustaining voltage $V_{CEO}^{(sus)}$ **MUST NOT** be measured on a curve tracer and measured by means of the test circuit shown in Fig.3

c $I_{S/b}$ is defined as the current at which second breakdown occurs at a specified collector voltage with the emitter-base junction forward-biased for transistor operation in the active region

d $I_{B1} = -I_{B2} =$ value shown

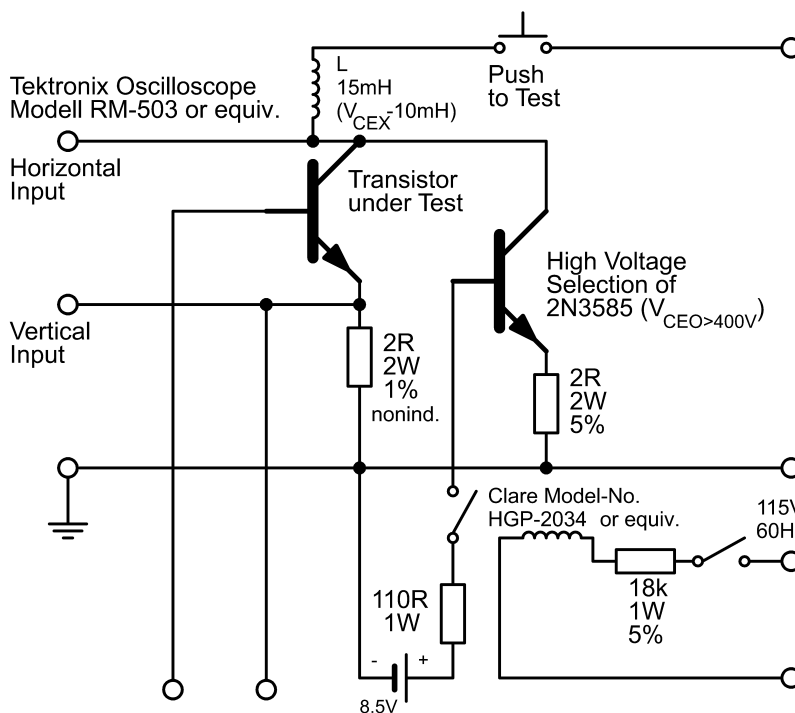
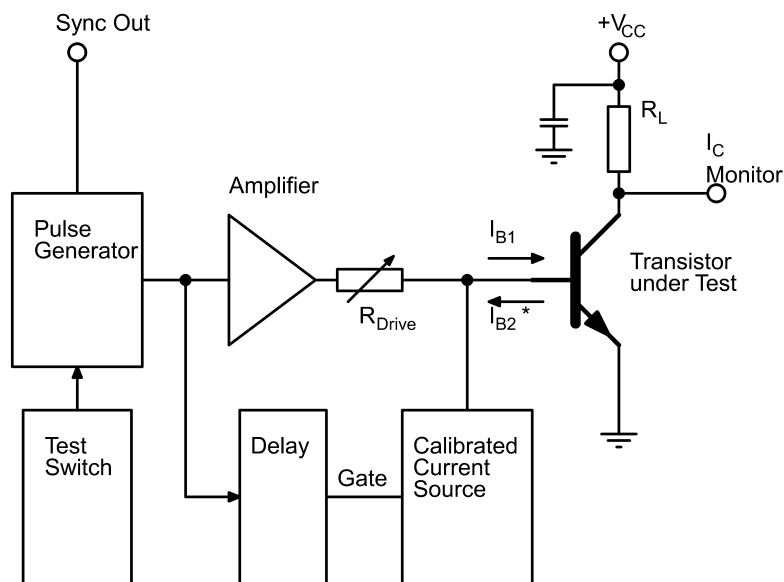


Fig. 3 Circuit used to measure sustaining voltage, $V_{CE0(sus)}$



* I_{B1} and I_{B2} measured with tektronix current probe P6019 or equivalent

Circuit used to measure switching time (t_r, t_s, t_f)

RCA413

I_C	- continuous collector current
I_{CM}	- peak collector current
I_{CER}	- collector-cutoff current with specified resistance between base and emitter
I_{CEX}	- collector-cutoff current with specified circuit between base and emitter
I_B	- continuous base current
I_{EBO}	- emitter-cutoff current, collector open
$I_{S/b}$	- forward-bias, second break-down collector current
V_{CBO}	- collector-to-base voltage, emitter open
V_{CEO}	- collector-to-emitter voltage, base open
$V_{CEO}^{(sus)}$	- collector-to-emitter sustaining voltage, base open
$V_{CER}^{(sus)}$	- collector-to-emitter sustaining voltage with specified resistance between base and emitter
V_{EBO}	- emitter-to-base voltage, collector open
V_{BE}	- base-to-emitter voltage
V_{CE}^{sat}	- collector-to-emitter saturation voltage
C_{OB}	- common-base output capacitance
C_{OBO}	- open circuit common-base output capacitance
f_T	- gain-bandwidth product (unity-gain frequency for devices in which gain roll-off has a -1 slope)
h_{FE}	- dc forward-current transfer ratio
$ h_{fe} $	- magnitude of common-emitter, small-signal, short-circuit, forward-current transfer ratio
R_{BE}	- external base-to-emitter resistance
$R_{\theta JC}$	- thermal resistance, junction-to-case
P_T	- transistor dissipation at specified temperature
t_f	- fall time
t_r	- rise time
t_s	- storage time
T_C	- case temperature
T_{stg}	- storage temperature
T_J	- operating (junction) temperature
T_L	- lead temperature during soldering
θ	- conduction angle